Session Program

2–4 Jun 2008

12th RD50 Workshop

Defect and Material Characterization

Ljubljana, Slovenia

Monday 2 June

09:30

Defect and Material Characterization

Session | **Location:** Ljubljana, Slovenia

09:30–10:00 **Overview of results from the WODEAN collaboration**

Speaker
Gordon Davies

10:00–10:20
Analysis of deep level system transformation by photoionization spectroscopy

Speaker
Prof. Juozas Vaitkus

10:20–10:40 **Study of cluster related effects in n-irradiated Epi-Do and MCz diodes**

Speaker
Alexandra Junkes

10:40–11:10 **Coffee Break**

11:10–11:30
Fluence and isochronal anneal dependent variations of recombination and DLTS characteristics in neutron and proton irradiated MCz , FZ and epi-Si structures

Speaker
Prof. Juozas Vaitkus

11:30–12:00 **Discussion Session on Defect and Material Characterization**

Speakers
Gordon Davies, Mara Bruzzi

12:00–13:30 **Lunch Break**

13:30